









TPD1E01B04-Q1 SLVSG26A - MAY 2021 - REVISED DECEMBER 2021

TPD1E01B04-Q1 Automotive 0.2-pF, ±3.6-V, ±15-kV **ESD Protection Diode in 0402 Package**

1 Features

- IEC 61000-4-2 level 4 ESD protection
 - ±15-kV contact discharge
 - ±17-kV air gap discharge
- IEC 61000-4-4 EFT protection
 - 80 A (5/50 ns)
- IEC 61000-4-5 surge protection
 - 2.5 A (8/20 µs)
- IO capacitance:
 - 0.20 pF (typical)
 - 0.23 pF (maximum)
- DC breakdown voltage: 6.4 V (typical)
- Ultra low leakage current: 10-nA (maximum)
- Low ESD clamping voltage: 15 V at 16 A TLP
- Low insertion loss: 20 GHz
- Supports high speed interfaces up to 20 Gbps
- Industry standard 0402 footprint
- AEC-Q101 qualified
 - Device HBM classification level H2
 - Device CDM classification level C5
 - Device operating temperature range: -40°C to +125°C

2 Applications

- End equipment
 - Surround view systems
 - ADAS vision systems
 - Rear view camera
 - Infotainment and cluster
 - Body control module
 - Head units
- Interfaces
 - Automotive SerDes: FPD-Link
 - USB Type-C
 - USB 3.1 Gen 2/3.0/2.0
 - HDMI 2.0/1.4
 - 10/100/1000 Mbps ethernet

3 Description

The TPD1E01B04-Q1 is a bidirectional TVS ESD protection diode for USB Type-C and FPD-Link circuit protection. The TPD1E01B04-Q1 is rated to dissipate ESD strikes at the maximum level specified in the IEC 61000-4-2 international standard (Level 4).

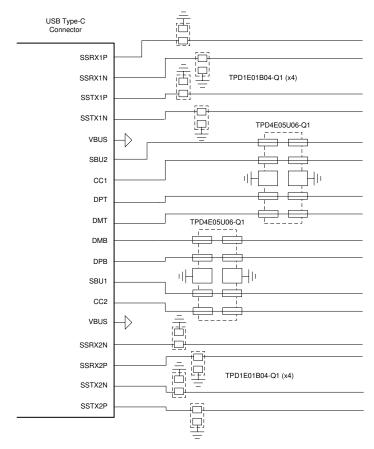
This device features a 0.20-pF (typical) IO capacitance making it ideal for protecting high-speed interfaces up to 20 Gbps such as USB 3.1 Gen2 and FPD-Link. The low dynamic resistance and low clamping voltage ensure system level protection against transient events.

The TPD1E01B04-Q1 is offered in the industry standard 0402 (DPY) package.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TPD1E01B04-Q1	X1SON (2)	1.00 mm x 0.60 mm

For all available packages, see the orderable addendum at the end of the data sheet.



Typical Application



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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (May 2021) to Revision A (December 2021)

Page



5 Pin Configuration and Functions

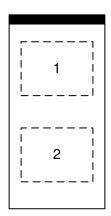


Figure 5-1. DPY Package 2-Pin X1SON Top View

Table 5-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION	
NO.	NAME	ITPE\/	DESCRIPTION	
1	Ю	I/O	ESD Protected Channel. If used as ESD IO, connect pin 2 to ground	
2	Ю	I/O	ESD Protected Channel. If used as ESD IO, connect pin 1 to ground	

(1) I = input, O = output



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Electrical fast transient	IEC 61000-4-5 (5/50 ns) at 25°C		80	Α
Peak pulse	IEC 61000-4-5 power (t _p - 8/20 μs) at 25°C		27	W
reak puise	IEC 61000-4-5 current (t _p - 8/20 μs) at 25°C		2.5	Α
T _A	Operating free-air temperature	-40	125	°C
T _{stg}	Storage temperature	-65	155	°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings—AEC Specification

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per AEC Q101-001	±2500	V
	Liectiostatic discharge	Charged device model (CDM), per AEC Q101-005	±1000	v

6.3 ESD Ratings—IEC Specification

			VALUE	UNIT
V	Electrostatic discharge	IEC 61000-4-2 Contact Discharge, all pins	±15000	
V _(ESD)		IEC 61000-4-2 Air-gap Discharge, all pins	±17000	V

6.4 ESD Ratings—ISO Specification

				VALUE	UNIT
V _(ESD)	Electrostatic discharge ISO 10605,	ISO 10605, 330-pF, 330-Ω, IO	Contact discharge	± 12500	V
		13O 10003, 330-pr , 330-sz, 1O	Air-gap discharge	±15000	

6.5 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V _{IO}	Input pin voltage	-3.6	3.6	V
T _A	Operating free-air temperature	-40	125	°C

6.6 Thermal Information

		TPD1E01B04-Q1	
	THERMAL METRIC ⁽¹⁾	DPY (X1SON)	UNIT
		2 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	442.6	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	243.8	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	162.5	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	154.1	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	163.0	°C/W

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6.6 Thermal Information (continued)

		TPD1E01B04-Q1	
	THERMAL METRIC ⁽¹⁾	DPY (X1SON)	UNIT
		2 PINS	
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	n/a	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

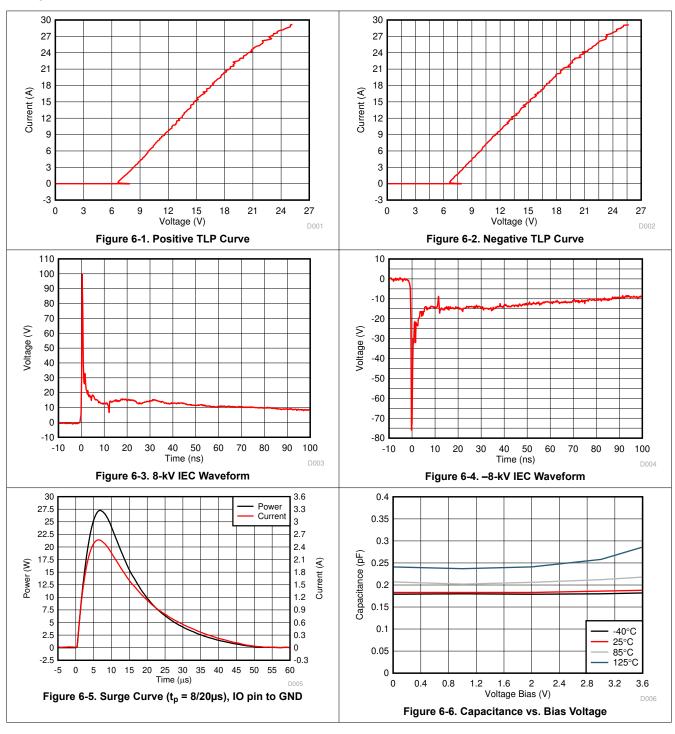
6.7 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{RWM}	Reverse stand-off voltage	I _{IO} < 10 nA	-3.6		3.6	V
V _{BRF}	Breakdown voltage, IO pin to GND	Measured as the maximum voltage		6.4		V
V_{BRR}	Breakdown voltage, GND to IO pin	before device snaps back into V _{HOLD} voltage		-6.4		V
V _{HOLD}	Holding voltage	I _{IO} = 1 mA, T _A = 25°C	5	5.9	6.5	V
	Clamping voltage	I _{PP} = 1 A, TLP, from IO to GND		7		
		I _{PP} = 5 A, TLP, from IO to GND		9.2		V
.,		I _{PP} = 16 A, TLP, from IO to GND		15		
V_{CLAMP}		I _{PP} = 1 A, TLP, from GND to IO		7		V
		I _{PP} = 5 A, TLP, from GND to IO		9.2		
		I _{PP} = 16 A, TLP, from GND to IO		15		
I _{LEAK}	Leakage current, IO to GND	V _{IO} = ±2.5 V			10	nA
	Dimension points and	IO to GND	0.5	0.57		
R_{DYN}	Dynamic resistance	GND to IO		0.57		Ω
CL	Line capacitance	$V_{IO} = 0$ V, f = 1 MHz, IO to GND, T_A = 25°C		0.2	0.23	pF

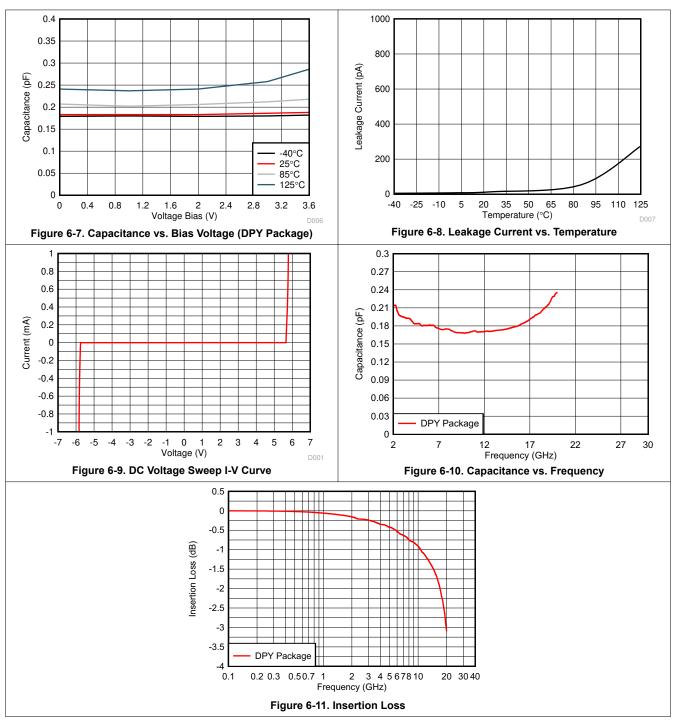


6.8 Typical Characteristics





6.8 Typical Characteristics (continued)





7 Detailed Description

7.1 Overview

The TPD1E01B04-Q1 device is a bidirectional ESD Protection Diode with ultra-low capacitance. This device can dissipate ESD strikes above the maximum level specified by the IEC 61000-4-2 International Standard. The ultra-low capacitance makes this device ideal for protecting any super high-speed signal pins including Thunderbolt 3. The low capacitance allows for extremely low losses even at RF frequencies such as USB 3.1 Gen 2, Thunderbolt 3, or antenna applications.

7.2 Functional Block Diagram



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7.3 Feature Description

7.3.1 IEC 61000-4-2 ESD Protection

The I/O pins can withstand ESD events up to ±15-kV contact and ±17-kV air gap. An ESD-surge clamp diverts the current to ground.

7.3.2 IEC 61000-4-4 EFT Protection

The I/O pins can withstand an electrical fast transient burst of up to 80 A (5/50 ns waveform, 4 kV with $50-\Omega$ impedance). An ESD-surge clamp diverts the current to ground.

7.3.3 IEC 61000-4-5 Surge Protection

The I/O pins can withstand surge events up to 2.5 A and 27 W (8/20 µs waveform). An ESD-surge clamp diverts this current to ground.

7.3.4 IO Capacitance

The capacitance between each I/O pin to ground is 0.2 pF (typical) and 0.23 pF (maximum). This device supports data rates up to 20 Gbps.

7.3.5 DC Breakdown Voltage

The DC breakdown voltage of each I/O pin is ± 6.4 V (typical). This ensures that sensitive equipment is protected from surges above the reverse standoff voltage of ± 3.6 V.

7.3.6 Ultra Low Leakage Current

The I/O pins feature an ultra-low leakage current of 10 nA (maximum) at a bias voltage of ±2.5 V.

7.3.7 Low ESD Clamping Voltage

The I/O pins feature an ESD clamp that is capable of clamping the voltage to 9.2 V ($I_{PP} = 5 \text{ A}$).

7.3.8 Supports High Speed Interfaces

This device is capable of supporting high speed interfaces up to 20 Gbps, because of the extremely low IO capacitance.

7.3.9 Industrial Temperature Range

This device features an industrial operating range of –40°C to +125°C.

7.3.10 Easy Flow-Through Routing Package

The layout of this device makes it simple and easy to add protection to an existing layout. The packages offers flow-through routing, requiring minimal modification to an existing layout.

7.4 Device Functional Modes

The TPD1E01B04-Q1 device is a passive integrated circuit that triggers when voltages are above V_{BRF} or below V_{BRR} . During ESD events, voltages as high as ± 17 kV (air) can be directed to ground through the internal diode network. When the voltages on the protected line fall below the trigger levels of TPD1E01B04-Q1 (usually within 10s of nano-seconds) the device reverts to passive.

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The TPD1E01B04-Q1 is a diode type TVS which is used to provide a path to ground for dissipating ESD events on high-speed signal lines between a human interface connector and a system. As the current from ESD passes through the TVS, only a small voltage drop is present across the diode. This is the voltage presented to the protected IC. The low R_{DYN} of the triggered TVS holds this voltage, V_{CLAMP} , to a safe level for the protected IC.

8.2 Typical Application

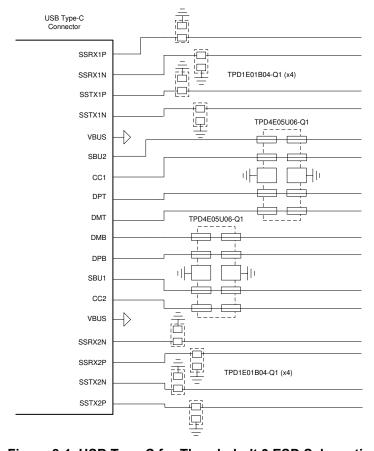


Figure 8-1. USB Type-C for Thunderbolt 3 ESD Schematic



8.2.1 Design Requirements

For this design example eight TPD1E01B04-Q1 devices and two TPD4E05U06-Q1 devices are being used in a USB Type-C for Thunderbolt 3 application. This provides a complete ESD protection scheme.

Given the Thunderbolt 3 application, the parameters listed in Table 8-1 are known.

Table 8	-1.	Design	Param	eters
---------	-----	--------	--------------	-------

DESIGN PARAMETER	VALUE				
Signal range on superspeed Lines	0 V to 3.6 V				
Operating frequency on superspeed Lines	up to 10 GHz				
Signal range on CC, SBU, and DP/DM Lines	0 V to 5 V				
Operating frequency on CC, SBU, and DP/DM Lines	up to 480 MHz				

8.2.2 Detailed Design Procedure

8.2.2.1 Signal Range

The TPD1E01B04-Q1 supports signal ranges between -3.6 V and 3.6 V, which supports the SuperSpeed pairs on the USB Type-C application. The TPD4E05U06-Q1 supports signal ranges between 0 V and 5.5 V, which supports the CC, SBU, and DP-DM lines.

8.2.2.2 Operating Frequency

The TPD1E01B04-Q1 has a 0.2 pF (typical) capacitance, which supports the Thunderbolt 3 data rates of 20 Gbps. The TPD4E05U06-Q1 has a 0.5-pF (typical) capacitance, which easily supports the CC, SBU, and DP-DM data rates.

8.2.3 Application Curves

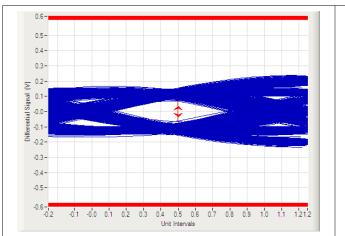


Figure 8-2. USB 3.1 Gen 2 10-Gbps Eye Diagram (Bare Board)

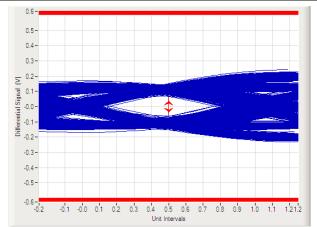


Figure 8-3. USB 3.1 Gen 2 10-Gbps Eye Diagram (with TPD1E01B04-Q1)

9 Power Supply Recommendations

This device is a passive ESD device so there is no need to power it. Take care not to violate the recommended I/O specification to ensure the device functions properly.

10 Layout

10.1 Layout Guidelines

- The optimum placement is as close to the connector as possible.
 - EMI during an ESD event can couple from the trace being struck to other nearby unprotected traces, resulting in early system failures.
 - The PCB designer must minimize the possibility of EMI coupling by keeping any unprotected traces away from the protected traces which are between the TVS and the connector.
- Route the protected traces as straight as possible.
- Eliminate any sharp corners on the protected traces between the TVS and the connector by using rounded corners with the largest radii possible.
 - Electric fields tend to build up on corners, increasing EMI coupling.

10.2 Layout Example

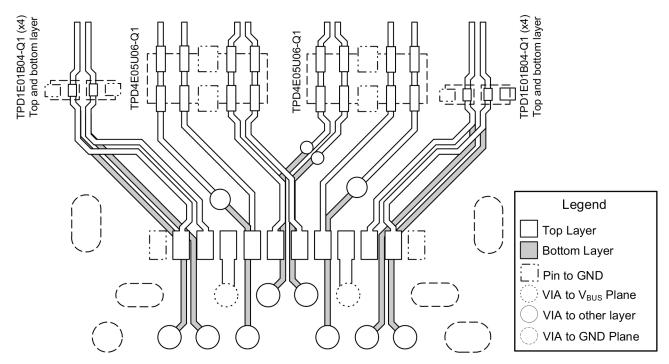


Figure 10-1. USB Type-C Mid-Mount, Hybrid Connector ESD Layout

11 Device and Documentation Support

11.1 Documentation Support

11.1.1 Related Documentation

For related documentation, see the following:

· Texas Instruments, Generic ESD Evaluation Module user's guide

11.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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11.4 Trademarks

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11.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
TPD1E01B04DPYRQ1	Active	Production	X1SON (DPY) 2	10000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	LR
TPD1E01B04DPYRQ1.B	Active	Production	X1SON (DPY) 2	10000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	LR

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF TPD1E01B04-Q1:

Catalog: TPD1E01B04

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

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NOTE: Qualified Version Definitions:

 $_{\bullet}$ Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPD1E01B04DPYRQ1	X1SON	DPY	2	10000	178.0	8.4	0.7	1.15	0.47	2.0	8.0	Q1

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*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
I	TPD1E01B04DPYRQ1	X1SON	DPY	2	10000	205.0	200.0	33.0	

1 x 0.6 mm

PLASTIC SMALL OUTLINE - NO LEAD

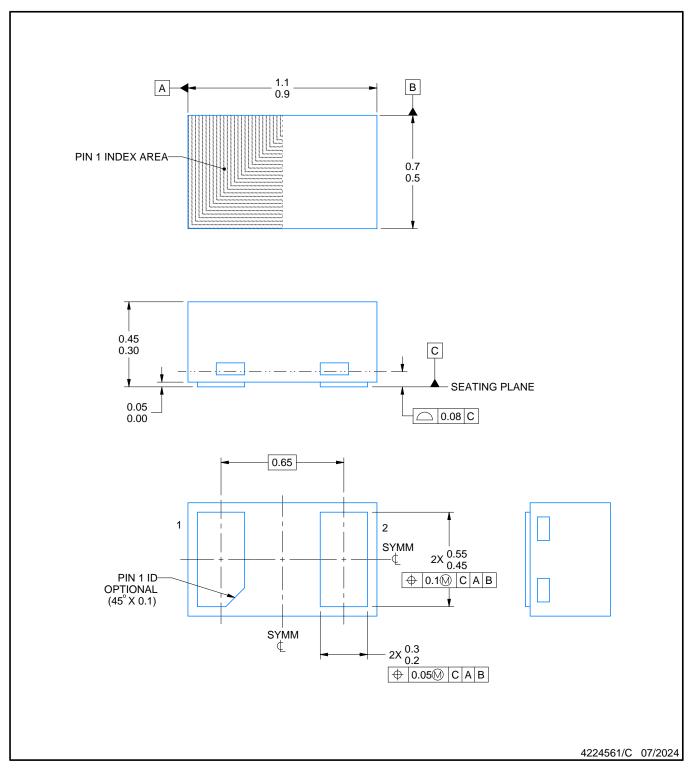
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC SMALL OUTLINE - NO LEAD

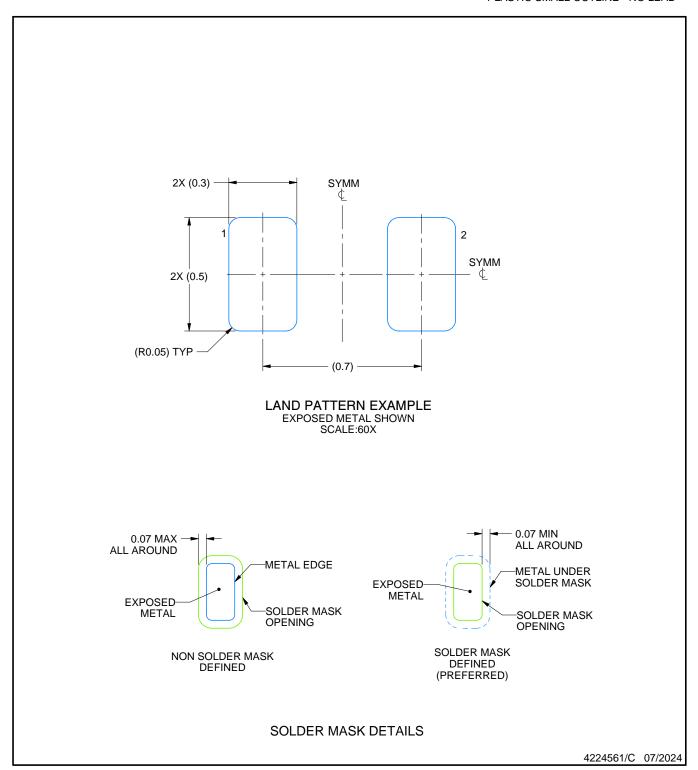


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M
- per ASME Y14.5M
 2. This drawing is subject to change without notice.



PLASTIC SMALL OUTLINE - NO LEAD

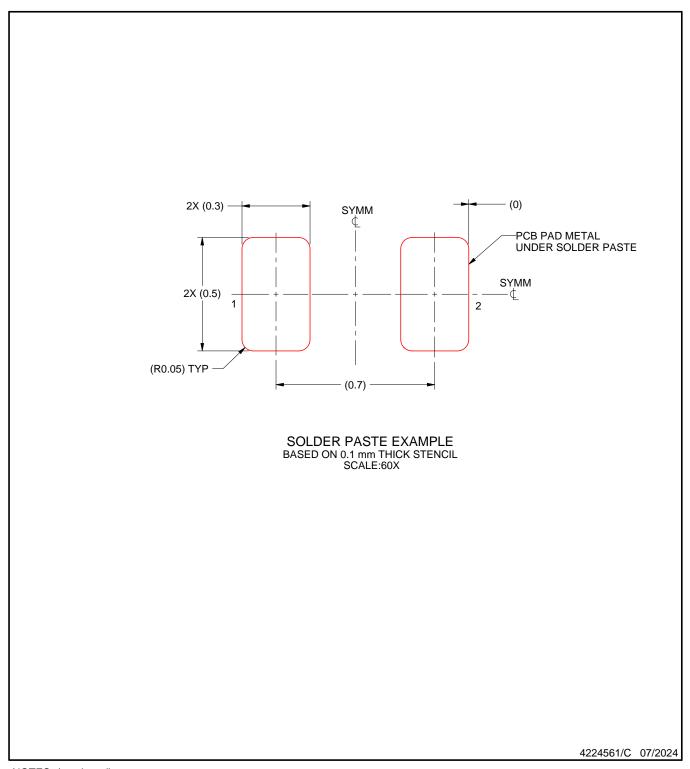


NOTES: (continued)

- 3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).4. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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